MOSFET - Power, Single N-Channel, μ8FL

30 V, 2.25 mΩ, 162 A

NVTFS4C02N

Features

- Low R_{DS(on)} to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- Optimized Gate Charge to Minimize Switching Losses
- NVTFS4C02NWF Wettable Flanks Option for Enhanced Optical
- AEC-Q101 Qualified and PPAP Capable
- These Devices are Pb-Free, Halogen Free/BFR Free and are RoHS Compliant

Applications

- Reverse Battery Protection
- DC-DC Converter Output Driver

MAXIMUM RATINGS (T_J = 25°C unless otherwise stated)

Paran	Symbol	Value	Unit		
Drain-to-Source Voltage	V_{DSS}	30	٧		
Gate-to-Source Voltage	V_{GS}	±20	V		
Continuous Drain		T _A = 25°C	I _D	28.3	Α
Current R _{θJA} (Note 1)		T _A = 100°C		20	
Power Dissipation		T _A = 25°C	P _D	3.2	W
R _{θJA} (Note 2)	Steady	T _A = 100°C		1.6	W
Continuous Drain	State	T _C = 25°C	I _D	162	Α
Current R _{θJC} (Note 1)		T _C = 100°C		115	
Power Dissipation		T _C = 25°C	P _D	107	W
R _{θJC} (Note 1)		T _C = 100°C		53.5	W
Pulsed Drain Current	T _A = 25°	C, t _p = 10 μs	I _{DM}	500	Α
Operating Junction and S Range	T _J , T _{stg}	-55 to +175	°C		
Source Current (Body Die	I _S	100	Α		
Drain to Source dV/dt	dV/dt	6.0	V/ns		
Single Pulse Drain-to-So (I _L = 37 A _{pk}) (Note 3)	E _{AS}	162	mJ		
Lead Temperature for So (1/8" from case for 10 s)	TL	260	°C		

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

- 1. Surface-mounted on FR4 board using 1 sq-in pad, 1 oz Cu.
- 2. Surface-mounted on FR4 board using the minimum recommended pad size.
- 3. This is the absolute maximum ratings. Parts are 100% tested at $T_J = 25$ °C, $V_{GS} = 10 \text{ V}, I_L = 36 \text{ A}, E_{AS} = 65 \text{ mJ}.$

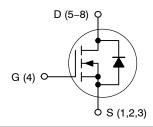


ON Semiconductor®

www.onsemi.com

V _{(BR)DSS}	R _{DS(on)} MAX	I _D MAX		
30 V	2.25 m Ω @ 10 V	162 A		
	3.1 mΩ @ 4.5 V	102 A		

N-Channel MOSFET





MARKING DIAGRAM



4C02 = Specific Device Code 02WF = Specific Device Code of NVTFS4C02NWF = Assembly Location

= Year WW = Work Week = Pb-Free Package

(Note: Microdot may be in either location)

ORDERING INFORMATION

Device	Package	Shipping [†]		
NVTFS4C02NTAG	WDFN8	1500 / Tape &		
NVTFS4C02NWFTAG	(Pb-Free)	Reel		

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

THERMAL RESISTANCE MAXIMUM RATINGS

Parameter		Value	Unit
Junction-to-Case (Drain)	$R_{ heta JC}$	1.4	°C/W
Junction-to-Ambient - Steady State	$R_{ heta JA}$	46	C/VV

ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS	•						•
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	V _{GS} = 0 V, I _D = 250 μA		30			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V _{(BR)DSS} / T _J				13.8		mV/°0
Zero Gate Voltage Drain Current	I _{DSS}	V _{GS} = 0 V,	T _J = 25°C			1.0	†
	$V_{DS} = 24 \text{ V}$ $T_{J} =$		T _J = 125°C			10	μΑ
Zero Gate Voltage Drain Current	I _{DSS}	V _{GS} = 0 V, V _{DS} = 30 V	T _J = 25°C			10	μΑ
Gate-to-Source Leakage Current	I _{GSS}	V _{DS} = 0 V, V _{GS}	_S = 20 V			100	nA
ON CHARACTERISTICS (Note 4)							
Gate Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}, I_D$	= 250 μΑ	1.3	1.6	2.2	V
Negative Threshold Temperature Coefficient	V _{GS(TH)} /T _J				5.0		mV/°
Drain-to-Source On Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 20 A		1.9	2.25	~ 0
		V _{GS} = 4.5 V	I _D = 20 A		2.7	3.1	mΩ
Forward Transconductance	9FS	V _{DS} = 1.5 V, I _D = 50 A			140		S
Gate Resistance	R_{G}				0.9		Ω
CHARGES AND CAPACITANCES							
Input Capacitance	C _{ISS}				2980		
Output Capacitance	C _{OSS}	V _{GS} = 0 V, f = 1 MHz, V _{DS} = 15 V			1200		pF
Reverse Transfer Capacitance	C _{RSS}				55		
Output Charge	Q _{OSS}	$V_{GS} = 0 \text{ V}, V_{D}$	_D = 15 V		25		nC
Capacitance Ratio	C _{RSS} /C _{ISS}	V _{GS} = 0 V, V _{DS} = 15	5 V, f = 1 MHz		0.018		
Total Gate Charge	Q _{G(TOT)}				20		
Threshold Gate Charge	Q _{G(TH)}	V _{GS} = 4.5 V, V _{DS} = 15 V; I _D = 50 A			4.7		nC
Gate-to-Source Charge	Q _{GS}				8.5		
Gate-to-Drain Charge	Q_{GD}				4		
Gate Plateau Voltage	V_{GP}				2.8		V
Total Gate Charge	Q _{G(TOT)}	V _{GS} = 10 V, V _{DS} = 15 V; I _D = 50 A			45		nC
SWITCHING CHARACTERISTICS (Note 5)							
Turn-On Delay Time	t _{d(ON)}	$V_{GS} = 4.5 \text{ V}, V_{DS} = 15 \text{ V},$ $I_{D} = 50 \text{ A}, R_{G} = 3.0 \Omega$			12		
Rise Time	t _r				116		ns
Turn-Off Delay Time	t _{d(OFF)}				25		
Fall Time	t _f				10		

^{4.} Pulse Test: pulse width \leq 300 μ s, duty cycle \leq 2%. 5. Switching characteristics are independent of operating junction temperatures.

ELECTRICAL CHARACTERISTICS ($T_J = 25^{\circ}C$ unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
SWITCHING CHARACTERISTICS (N	ote 5)				•	•	
Turn-On Delay Time	t _{d(ON)}				9		
Rise Time	t _r	V _{GS} = 10 V, V _D		102		ns	
Turn-Off Delay Time	t _{d(OFF)}	$I_D = 50 \text{ A}, R_G = 3.0 \Omega$			33		
Fall Time	t _f			6			
DRAIN-SOURCE DIODE CHARACT	ERISTICS						
Forward Diode Voltage	V_{SD}	$V_{GS} = 0 \text{ V},$ $I_S = 20 \text{ A}$ $T_J = 25^{\circ}\text{C}$ $T_J = 125^{\circ}\text{C}$			0.8	1.1	\ /
					0.6		V
Reverse Recovery Time	t _{RR}	$V_{GS} = 0 \text{ V, } dI_{S}/dt = 100 \text{ A/}\mu\text{s,}$ $I_{S} = 50 \text{ A}$			42		
Charge Time	t _a				21		ns
Discharge Time	t _b				21		
Reverse Recovery Charge	Q_RR			28		nC	

^{4.} Pulse Test: pulse width \leq 300 μ s, duty cycle \leq 2%.

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

^{5.} Switching characteristics are independent of operating junction temperatures.

TYPICAL CHARACTERISTICS

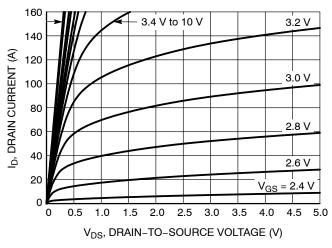


Figure 1. On-Region Characteristics

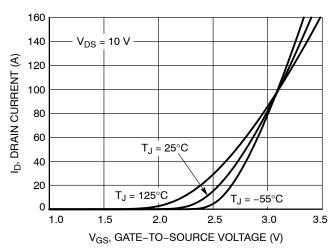


Figure 2. Transfer Characteristics

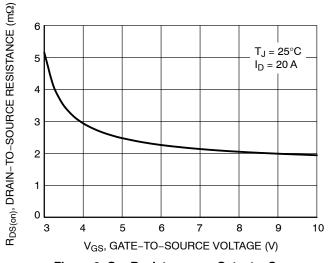


Figure 3. On-Resistance vs. Gate-to-Source Voltage

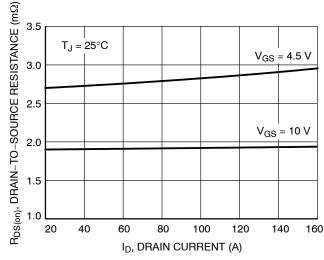


Figure 4. On-Resistance vs. Drain Current and Gate Voltage

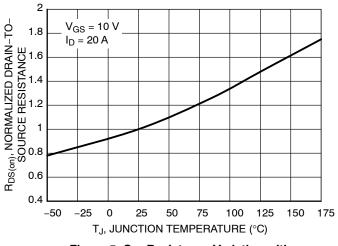


Figure 5. On–Resistance Variation with Temperature

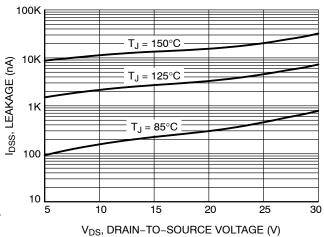


Figure 6. Drain-to-Source Leakage Current vs. Voltage

TYPICAL CHARACTERISTICS

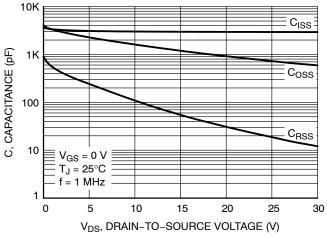


Figure 7. Capacitance Variation

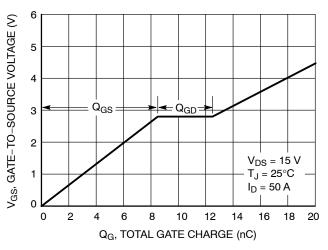


Figure 8. Gate-to-Source vs. Total Charge

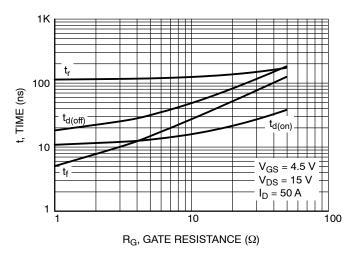


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

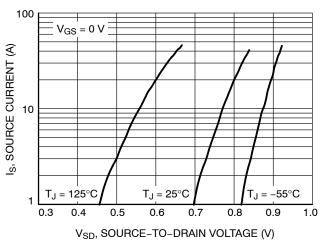


Figure 10. Diode Forward Voltage vs. Current

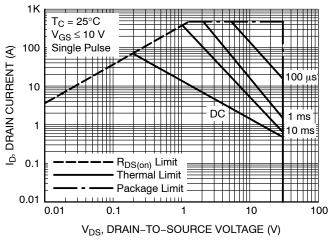


Figure 11. Maximum Rated Forward Biased Safe Operating Area

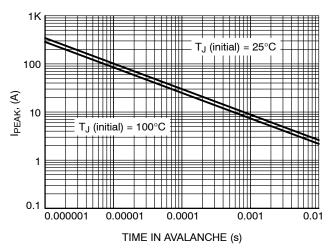


Figure 12. I_{PEAK} vs. Time in Avalanche

TYPICAL CHARACTERISTICS

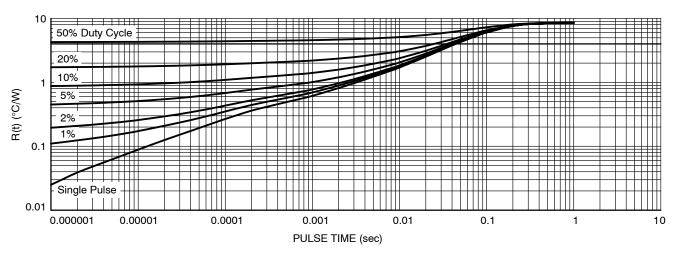
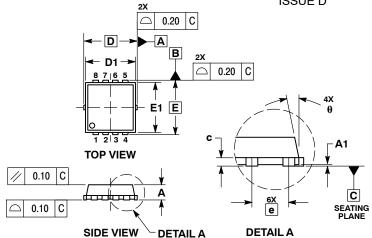


Figure 13. Thermal Characteristics

PACKAGE DIMENSIONS

WDFN8 3.3x3.3, 0.65P

CASE 511AB ISSUE D



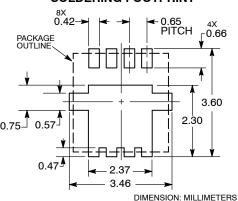
NOTES

- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
 2. CONTROLLING DIMENSION: MILLIMETERS.
 3. DIMENSION D1 AND E1 DO NOT INCLUDE MOLD FLASH PROTRUSIONS OR GATE BURRS

	MILLIMETERS				INCHES		
DIM	MIN	NOM	MAX	MIN	NOM	MAX	
Α	0.70	0.75	0.80	0.028	0.030	0.031	
A1	0.00		0.05	0.000		0.002	
b	0.23	0.30	0.40	0.009	0.012	0.016	
C	0.15	0.20	0.25	0.006	0.008	0.010	
D		3.30 BSC		0.130 BSC			
D1	2.95	3.05	3.15	0.116	0.120	0.124	
D2	1.98	2.11	2.24	0.078	0.083	0.088	
E		3.30 BSC	;	0.130 BSC			
E1	2.95	3.05	3.15	0.116	0.120	0.124	
E2	1.47	1.60	1.73	0.058	0.063	0.068	
E3	0.23	0.30	0.40	0.009	0.012	0.016	
е		0.65 BSC	;	(0.026 BS0	0	
G	0.30	0.41	0.51	0.012	0.016	0.020	
K	0.65	0.80	0.95	0.026	0.032	0.037	
L	0.30	0.43	0.56	0.012	0.017	0.022	
L1	0.06	0.13	0.20	0.002	0.005	0.008	
М	1.40	1.50	1.60	0.055	0.059	0.063	
θ	0 °		12 °	0 °		12 °	

С 0.10 Α В 0.05 С 4X I E2 E3 <u></u> D2 **BOTTOM VIEW**

SOLDERING FOOTPRINT*



*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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